

<b>Form PTO-1449</b>  <b>INFORMATION DISCLOSURE CITATION IN AN APPLICATION</b>  <i>(Use several sheets if necessary)</i>				<b>Docket Number (Optional)</b> <b>5157.1US (01-1004.01/US)</b>		<b>Application Number</b> <b>Not yet assigned</b>	
				<b>Applicant</b> <b>J ffery N. Gl ason</b>			
				<b>Filing Date</b> <b>October 20, 2003</b>		<b>Group Art Unit</b> <b>Unknown</b>	

  

U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
W	5,203,911	04/1993	Sricharoenchaikit et al.	Z		
	5,258,062	11/1993	Nakazawa et al.			
	6,043,966	03/2000	Krueger et al.			
	6,235,557 B1	05/2001	Manley			
	6,277,674 B1	08/2001	Wang et al.			
	6,300,242 B1	10/2001	Ueda et al.			
	6,323,534 B1	11/2001	Marr et al.			
	6,335,626 B1	01/2002	Motulla			
	2002/0011666 A1	01/2002	Tandy			
	2003/0003703 A1	01/2003	Barth et al.			

  

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						YES	NO

  

OTHER DOCUMENTS		(Including Author, Title, Date, Pertinent Pages, Etc.)
		HENDERSON, Christopher L., et al., "The Behavior and Testing Implications of CMOS IC Open Circuits," Proc. International Test Conference, (1991), pp. 1-11.
		INCO Newsletter, "Nickel Currents," Vol. 8, No. 2, (1999), pp. 1-4.
		Cascade Microtech Technical Data Sheet, "Challenges of Conventional Wafer Probing," (2002).

  

<b>EXAMINER</b> <i>Wkhi Truh</i>	<b>DATE CONSIDERED</b> <i>4/7/05</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.